

INTERNATIONAL QUALITY AND ACCREDITATION SERVICES PVT. LTD.
(Formerly International Quality And Accreditation Services LLP)



Certificate No.: T-0042

Date: 30.03.2026
Validity: 29.03.2030

ACCREDITATION CERTIFICATE

This is to certify that

Salicon Nano Technology Pvt. Ltd.

following assessment, is accredited in accordance with international standard

ISO/IEC 17025:2017

"General Requirements for the Competence of Testing and Calibration Laboratories"

for its facilities* in the field of

'Testing – Electronics'



RATAN SINGH RANA
DIRECTOR, IQAS

This certificate is valid for the scope of Accreditation and facilities of the CAB accredited by IQAS

*Address of Facilities Accredited

Sr. No.	Address
1.	Pawan Puri, Sybly Industrial Area, Near Ganga Canel, Murad Nagar, Ghaziabad - 201206, U.P



Certificate

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Scope



Scope of Accreditation for Testing

As per ISO/IEC 17025:2017

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Address: Pawan Puri, Sybly Industrial Area, Near Ganga Canel,
Murad Nagar, Ghaziabad - 201206, U.P

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Amendment date: N/A

Sr. No.	Product or material or equipment used for test	Type of test performed/ characteristic	Range/ limit of detection	Standard specifications/ Equipment/Techniques used	Facility
1	Electronic/Electrical components/Electronic Sub-Assembly (ESA)	Conducted emission from components/ modules on HV power lines – Current probe method	150 kHz – 108 MHz	CISPR 25: Clause 6.4	Permanent
2	Electronic/Electrical components/Electronic Sub-Assembly (ESA)	Conducted emission from components/ modules on HV power lines – Voltage probe method	150 kHz – 108 MHz	CISPR 25: Clause 6.3.	Permanent
3	Electronic/Electrical components/Electronic Sub-Assembly (ESA)	Conducted Emissions from Components/ Modules	150 kHz – 108 MHz	CISPR 25: Clause 6.1	Permanent
4	Electronic/Electrical components/Electronic Sub-Assembly (ESA)	Conducted Emissions from Components/ Modules	150 kHz – 108 MHz	CISPR 25: Clause 6.1	Permanent
5	Electrical/Electronic sub assembly (ESA)	Radiated emissions from components/ modules	150 kHz – 2.5 GHz	CISPR 25: Clause 6.5	Permanent
6	Electronic/Electrical components/Electronic Sub-Assembly (ESA)	Radiated emissions from components/ modules – ALSE method	150 kHz – 2.5 GHz	CISPR 25: Clause 6.5	Permanent
7	Multimedia Equipment	Conducted Emissions	150 kHz – 30 MHz	CISPR 32:+AMD1: Clause 5	Permanent
8	Multimedia equipment	Radiated emissions	30 MHz – 6 GHz	CISPR 32:+AMD1: Clause 6	Permanent
9	Electronic/Electrical components	Electrostatic discharge immunity test	±2 kV to ±8 kV(Contact)	IEC 61000-4-2: Clause 6 & 7	Permanent



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			±2 kV to ±15 kV(AIR)		
10	Electronic/Electrical components	Immunity to conducted disturbances, induced by radio-frequency fields	150 kHz – 80 MHz	IEC 61000-4-6: Clause 7	Permanent
11	Electronic/Electrical components	Radiated, radiofrequency, electromagnetic field immunity test	80 MHz – 6 GHz	IEC 61000-4-3: Clause 7	Permanent
12	Electronic/Electrical Components/Electronic Sub-Assembly (ESA)	Immunity to Electromagnetic Disturbance – Absorber Lined Shielded Enclosure	20 MHz – 2 GHz	AIS 004 (Part 3) Clause :5	Permanent
13	Défense Subsystem/Equipment	Radiated emissions, antenna spurious and harmonic outputs.	10 kHz – 40 GHz	RE103- MILSTD461E: /MILSTD/ 461F:/MIL-STD 461G: clause RE103	Permanent
14	Defense Subsystem/Equipment	Radiated emissions, magnetic field	30 Hz – 100 kHz	RE101-MIL-STD 461E:/MIL- STD 461F:/ MIL- STD 461G: clause RE101	Permanent
15	Defense Subsystem/Equipment	Radiated emissions, electric field	10 kHz – 18 GHz	RE102-MIL-STD 461E:/MIL- STD 461F:/ MIL- STD 461G: clause RE102	Permanent
16	Electric Vehicle Conductive AC Charging System	Conducted Emission Test	150 kHz – 30 MHz	AIS 138 Part 1:/AIS 138 Part 2:/ IEC 61851-1:/COR1: clause 7	Permanent
17	Electric Vehicle Conductive AC Charging	DC Voltage dips, Short Interruption & Voltage	0% to 100%	AIS 138 Part 2 : Clause 6.4	Permanent



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Sr. No.	Product or material or equipment used for test	Type of test performed/ characteristic	Range/ limit of detection	Standard specifications/ Equipment/Techniques used	Facility
	System	Variations Immunity test			
18	Electric Vehicle Conductive AC Charging System	Harmonic Current Emission test	Up to 40th Harmonic	AIS 138 Part 1: / IEC 61851-1:/COR1: Clause 12.	Permanent
19	Electric Vehicle Conductive AC Charging System	High Energy Immunity test	± 5 kV & ± 6 kV	AIS 138 Part 1:/AIS 138 Part 2:/ IEC 61851-21-2:/	Permanent
20	Electric Vehicle Conductive AC Charging System	Electrical Fast Transient (EFT)/ Burst Immunity test	1 kV – 4 kV	AIS 138 Part 1: Clause 12/AIS 138 Part 2 Clause 6	Permanent
21	Electric Vehicle Conductive AC Charging System	Electrical Fast Transient (EFT)/ Burst Immunity test	± 2 kV to ± 4 kV	IEC 61851-21-2: Clause 7	Permanent
22	Electric Vehicle Conductive AC Charging System	Conducted RF Susceptibility /Bulk Current Injection test	150 kHz – 230 MHz	IEC 61851-21-2: Clause 7	Permanent
23	Electrical Lighting & Similar Equipment	Conducted Emission	9 kHz – 30 MHz	BS EN 55015+A11:/BS clause Clause 4.3	Permanent
24	Electrical/Electronics sub assembly (ESA)	Conducted RF Susceptibility /Bulk Current Injection test	1 MHz – 400 MHz	ISO 11452- 4: Clause 6,7,8,9	Permanent
25	Electrical/Electronics Sub assembly (ESA) and Vehicle	Radiated Emission test	30 MHz – 1 GHz	AIS 138 Part 1:/ Part 2: / IEC 61851-21-2: Clause 6 & 7	Permanent
26	Electrical/Electronic Subassembly (ESA)	Conducted RF Susceptibility /Bulk Current Injection test	1 MHz – 400 MHz	ISO 11452-4: / AIS 004(Part3) rev 1 : clause 6 & 7	Permanent



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Sr. No.	Product or material or equipment used for test	Type of test performed/ characteristic	Range/ limit of detection	Standard specifications/ Equipment/Techniques used	Facility
27	Electrical/Electronic Product	Damped Oscillatory Magnetic Field test	100 kHz & 1 MHz Field Strength: 3 A/m – 100 A/m	IEC 61000-4-10: clause 6,7	Permanent
28	Electrical/Electronics subassembly and Vehicle	RF Radiated Susceptibility test	80 MHz – 6 GHz	IEC 61851-21-2: Clause 7.3	Permanent
29	Electrical/Electronics subassembly and Vehicle	Voltage dips, Short Interruption & Voltage Variations Immunity test	0% - 100%	IEC 61851-21-2: Clause 7	Permanent
30	Electrical/Electronics subassembly and Vehicle	Voltage Fluctuation & Flicker test	Voltage: 0–300 V AC (1-ph), 0–600 V AC (3-ph) Frequency: 50–60 Hz ,Pst: 0–10 ,Plt: 0–10 ,dmax: 0–10% d(t): 0–10% - dc: 0–5%	IEC 61851-21-2: Clause 6.2	Permanent
31	Electrical/ Electronics subassembly (ESA)	RF Radiated Susceptibility test	10 kHz – 18 GHz	AIS004: /ISO11452-2:/ISO 11452-2: Clauses 6–8	Permanent
32	Electrical/Electronics Product	Automotive Conducted Emission	150 kHz – 108 MHz	CISPR 25:/"standard CISPR 25: IEC61851-21-2: clause 6 /FO RD ES XW7T-1A278-AC/FORDFMC1278/	Permanent



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Sr. No.	Product or material or equipment used for test	Type of test performed/ characteristic	Range/ limit of detection	Standard specifications/ Equipment/Techniques used	Facility
				FORD FMC1280	
33	Electrical/Electronics Product	Automotive Electrical immunity test	12 V & 24 V	ISO 16750-2:, Clauses 4.2 to 4.7	Permanent
34	Electrical/Electronics Product	Automotive Electrical Transient Immunity test	Pulse Voltage: – 150 V to +200 V Transient Pulses: –150 V to +200 V	ISO 7637-2: clause 4,5,6, ISO 7637-2: clause 4 & 8 /FORD ES XW7T-1A278-AC/FORD FMC1278/FORD FMC1280/ /104/EC:/"standard "ISO 16750-2:/ISO 16750-2:/AIS 004(Part 3):+A1:/AIS 004(part 3):rev1:/ECE R10.05:/SAE J 1113-12:/ECER10.0	Permanent
35	Electrical/Electronics Product	Conducted Emission Test	150 kHz – 30 MHz	CISPR 11 + A1: + A2: clause 6.3/ CISPR14-1: Clause 6.2," Standard" CISPR 22:/CISPR 32 /CISPR 15:, Clause 4 & 5	Permanent
36	Electrical/Electronics Product	Conducted Emission Test	150 kHz – 30 MHz	IEC61800-3: clause 5.4 & 6.3/BS EN 61800-3: clause 5.4 & 6.3	Permanent
37	Electrical/Electronics Product	Conducted RF Susceptibility	150 kHz – 80 MHz	"Standard" IEC 61000-4-6:/IEC	Permanent



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Sr. No.	Product or material or equipment used for test	Type of test performed/ characteristic	Range/ limit of detection	Standard specifications/ Equipment/Techniques used	Facility
		/Bulk Current Injection test		61000-4-6:/ IEC 62040-2:/"Standard" IEC60255-26:/ IEC60255- 26:/"Standard" / IEC 62052-11:/ IEC 61000-6-1:/IEC 61000-6-2:/IEC 60601-1-2:+A1: /IEC 61000-6-5:/IEC 61851-21- 2:/"Standard" IEC 61800-3:/IEC 61800-3:/BS EN 61800-3:/ "Standard" CISPR 24:/CISPR 14-2:/CISPR 35:/ GR1089:	
38	Electrical/Electronics Product	Conducted Susceptibility test	10 kHz – 200 MHz	CS101/ CS103 /CS104/ CS105/ CS109/ CS114/CS115 /CS116 - MIL-STD 461E:/MIL-STD 461F:/MIL-STD 461G:/ CS106-MIL- STD 461F:/CS118-MIL- STD 461 G	Permanent
39	Electrical/Electronics Product	DC Voltage dips, Short Interruption & Voltage Variations Immunity test	0%-100%	IEC 61000-4- 29:2000/CISPR 35:/BS EN61000-4- 29:/BS EN 55035:+A11:/"standa rd" IEC 60255-26:/IEC	Permanent



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Sr. No.	Product or material or equipment used for test	Type of test performed/ characteristic	Range/ limit of detection	Standard specifications/ Equipment/Techniques used	Facility
				60255-26:	
40	Electrical/Electronic Product	Electrical Fast Transient (EFT)/ Burst Immunity test	5 kHz & 100 kHz Voltage: ± 250 V ± 4 kV	IEC 61000-4-4:/IEC 60601-1-2:+A1:clause 5-9/IEC 62040-2: clause 6/IEC 61000-6-2:clause 7/ "Standard" IEC60255-26:/IEC 60255-26:/clause 6 "Standard" IEC 62052-11: clause 8/IEC 61326-1: clause 8/IEC 255-22-4:/ IEC 61000-6-5: clause 7/"Standard" IEC 61800-3:/IEC 61800-3: / CISPR14-2: clause 7/CISPR 35: clause 7/ "Standard" CISPR 24: clause 7/IEEE C 62.45:/IEEE C 37.90.1:/ECER10.05: / EN ETSI 300 386/ECER10.06	Permanent
41	Electrical/Electronic Product	Electrical Fast Transient (EFT)/ Burst Immunity test	5 kHz – 100 kHz Repetition 250 V – 4 kV	BS EN 60601-1-2:+A1:/BS EN 55014-2: clause 7/BS EN 61000-4-4:+ A1: clause 5-9/BS EN	Permanent



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Sr. No.	Product or material or equipment used for test	Type of test performed/ characteristic	Range/ limit of detection	Standard specifications/ Equipment/Techniques used	Facility
				61000-6-2: clause 7/BS EN 62040-2:/clause 6"Standard" BS EN 61000-6-1: clause 7/BS EN 62052-11: clause 8/BS EN 55035:+A11:/BS EN 50121-3-2: A1:/ clause 6	
42	Electrical/Electronic Product	Electrostatic Discharge immunity test	± 2 kV to ± 30 kV	IEC 61000-4-2: + A1:, Clauses 5–9/IEC 61000-6-1: clause 7 /IEC 61000-6-2:/IEC 60601-1-2:+A1: clause 7 /IEC 62040-2: clause 6/ "Standard" /IEC 60255-26: clause 6 /"Standard" /IEC 62052-11: clause 8/IEC 61326-1: clause 8	Permanent
43	Electrical/Electronic Product	Electrostatic Discharge test	± 0.5 kV to ± 30 kV	CS118 clause Section 5.16- 5.16.1– 5.16.3 MIL-STD 461 G	Permanent
44	Electrical/Electronic Product	Harmonic Current Emission test	Up to 40th harmonic $\rightarrow 2$ kHz	IEC 61000-3-2: + A1:, Clauses 6, 7 and 8/IEC 60601-1-2: +A1: Clause 7/BS EN 60601-1-2:+A1:	Permanent



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International Quality And Accreditation Services Pvt. Ltd.
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1/4, 1st Floor, East Patel Nagar New Delhi, 110008

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Sr. No.	Product or material or equipment used for test	Type of test performed/ characteristic	Range/ limit of detection	Standard specifications/ Equipment/Techniques used	Facility
				clause 7/BS EN 62040-2: clause 5/BS EN 61000-3-2:+A1:/BS EN 61000-6-3: clause 7/IEC 62040-2:/ECE R10.05:/IEC 61000-6-3, clause 7	
45	Electrical/Electronic Product	Harmonics & Interharmonics immunity test	0 Hz – 2 kHz (harmonics + inter harmonics)	IEC 61000-4-13:+ A1:+A2 : Clauses 5 to 9./BS EN 61000-4-13: +A2: Clauses 5 to 9	Permanent
46	Electrical/Electronic Product	High Energy/ Telecom Surge Immunity test	Line–line: 0.5 kV – ±2 kV Line–earth: 0.5 kV – ±4 kV	CISPR 35: clause 9/IEEE C 62.45: clause 6/EN 50121-3-2 +A1 clause 6/TEC/SD/DD/EMC-221/05/ OCT-16/ETSI 300386: Clause 4.2	Permanent
47	Electrical/Electronic Product	High Energy/ Telecom Surge Immunity test	0.5 kV – 4 kV 1.2/50 µs surge waveform	IEC61000-4-5:+A1: clause 5-9," Standard" /IEC 60601-1-2:+A1: clause 8/IEC 61000-6-1: clause 7/IEC 61000-6-2: clause 8/IEC 62040-2: clause 6	Permanent



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Sr. No.	Product or material or equipment used for test	Type of test performed/ characteristic	Range/ limit of detection	Standard specifications/ Equipment/Techniques used	Facility
				/"Standard" IEC 60255-26: clause 6/IEC 60255-26:/IEC 62052-11:/ IEC 62052-11:/IEC 61326-1:/IEC 61000-6-5:/"Standard" IEC 61800-3:/IEC 61800-3:/BS EN 61800-3:/IEC 62236-3-2Clause 6	
48	Electrical/Electronic Product	Power Frequency Magnetic Field Immunity test	up to 100 A/m	Standard" CISPR 24:+A1:Clause 8 /CISPR35:20 16 clause 9/IEC 60601-1-2:+A1: clause 8 /"Standard" /IEC 60255-26:clause 6/IEC 61326-1:clause 8/IEC 62040-2: clause 6	Permanent
49	Electrical/Electronic Product	Pulse Magnetic field immunity test	Magnetic Field Strength: 10 A/m to 1000 A/m (as per IEC 61000-4-9) Pulse Rise Time: 5–100 ns	IEC 61000-4-9:/BS EN 62052-11: Clause 8 BS EN61000-4-9:/IEC 62052-	Permanent



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			Pulse Duration: 100–200 μ s Repetition Rate: Single pulse to 1 Hz	11:/"Standard" IEC 62052-11	
50	Electrical/Electronic Product	Radiated Emission test	30 MHz – 1 GHz	IEC 61000-6-3: Clause 6 IEC 61000-6-4: Clause 6 IEC 60601-1-2: +A1: Clause 7 IEC 62040-2: Clause 6 IEC 62052-11: Clause 8 IEC 60255-26: Clause 26 IEC 61800-3: Clause 6 IEC 61800-3: / Clause 7 BS EN 61800-3: / Clause 7 IEC 61326-1: / ETSI 300386: / TEC / SD / DD / EMC 221/05 / OCT-16 Section 4-5	Permanent
51	Electrical/Electronic Product	Radiated Emission test	10 kHz – 40 GHz	RE103-MIL-STD461E: / MIL-STD/461F: / MIL-STD 461G	Permanent
52	Electrical/Electronic Product	Radiated Emission test	30 MHz – 1 GHz	CISPR 11: Clause 8.3 & 9 CISPR 22: CISPR 32: +A1: / CISPR 14-	Permanent



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				1:Clause 4.3.2 - 4.3.5FCC 15B BS EN 55022:BS EN 55025:BS EN55025:BS EN55011:+A1:+A2:2 021/BS EN 61000-6- 3:/BS EN61000-6- 4:/BS EN55014- 1:/BS EN60601-1- 2:+A1:/BS EN 62040- 2:/BS EN 62052- 11:/BS EN 50121-4:+A1:/BS EN 55032:+A1:/" Standard" BS EN 50091-2:1996/BS EN 50121-3-2	
53	Electrical/Electronic Product	Radiated Susceptibility test	10 kHz – 2 MHz (low-frequency radiated susceptibility)2 MHz – 40 GHz (high-frequency radiated susceptibility)	RS101-MIL-STD 461E:/MIL- STD 461F:/ MIL-STD 461G:/RS103-MIL- STD 461E:/MIL-STD 461F:/MIL-STD 461G	Permanent
54	Electrical/Electronic Product	RF Radiated Susceptibility test	80 MHz – 6 GHz	""Standard" BS EN 55024:/BS EN 55014-2:/BS EN 61000-4-3:/BS EN	Permanent



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				60601-1-2:+A1:/ BS EN 61000-6-1:/BS EN 61000-6-2:/BS EN 62040-2:/BS EN 62052-11:/BS EN 50121-3-2:/ "Standard" BS EN 50091-2:1996/BS EN 50121-4:+A1:/IEEE C37.90.2:/TEC/SD/D D/EMC - 221/05/OCT-16/EN ETSI 300386:	
55	Electrical/Electronic Product	RF Radiated Susceptibility test	80 MHz – 6 GHz.	IIEC61000-4-3:/Clause 7-9 IEC 60601-1-2:+A1:/ Clause 8 IEC61000-6-1: Clause 7 IEC61000-6-2: Clause 7 /IEC 62040-2: Clause 5 /"Standard" IEC 60255-26: Clause 7 IEC60255-26:/ IEC 61326-1: Clause 7IEC 62052-11: Clause 6/IEC 61000-6-5:/ Clause	Permanent



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				8"Standard" IEC 61800-3:/ Clause 8IEC 61800-3:/ Clause 8BS EN 61800-3:/ Clause 77CISPR24: Clause 5 /CISPR 14-2:/GR 1089:/CISPR 35	
56	Electrical/Electronic Product	Ring Wave Immunity test(100 kHz)Damped Oscillatory Wave Immunity test(100 kHz,1MHz)	Ring Wave Immunity 100 kHz 0.5 kV – 6 kV (open circuit)Damped Oscillatory Wave-100 kHz0.25 kV – 2.5 kV1 MHz0.25 kV – 2.5 kV	IEC 61000-4-12: Clause5-7IEC62052-1 1:/IEC 61000-6-5:/BS EN 62052-11:/ BS EN 61000-4-12:/BS EN 60255-22-1: /BS EN 61000-4-18:Clause5-7IEC60255-26:IEC 255-4:1976/IEC 255-22-1:/IEEE C.37.90.1:/ IEEE C 62.45:/IEC 61000-4-18	Permanent
57	Electrical/Electronic Product	Ripple On DC Input Power Port immunity test	DC Voltage Range: 0–1000 V DC Ripple Frequency: 100 Hz – 100 kHz	IEC 61000-4-17:, BS EN 61000-4-17	Permanent



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Sr. No.	Product or material or equipment used for test	Type of test performed/ characteristic	Range/ limit of detection	Standard specifications/ Equipment/Techniques used	Facility
			Ripple Voltage Amplitude: 0.5% – 15%		
58	Electrical/Electronic Product	Voltage dips, Short Interruption & Voltage Variations Immunity test	0%-100%	IEC61000-4-11: Clause6-9CISPR 24: Clause5CISPR14-2: Clause6CISPR 35: Clause5IEC61000-6-1: Clause7IEC61000-6-2: Clause7IEC60255-26: Clause6/ IEC 60601-1-2:+A1: Clause8IEC62040-2: Clause5IEC61326-1: Clause8IEC61000-6-5: Clause 7	Permanent
59	Electrical/Electronic Product	Voltage Fluctuation & Flicker test	Voltage: 0–300 V AC (1-ph) Frequency: 50–60 Hz Pst: 0–10, Plt: 0–10 dmax: 0–10%, d(t): 0–10%, DC: 0–5%	IEC 61000-3-3: Clause 5-7BS EN 60601-1-2:+A1: Clause 7BS EN62040-2: Clause 6BS EN61000-6-3: Clause 6IEC60601-1-2:+A1: Clause 7IEC61000-6-3: Clause 6	Permanent
60	Electrical/Electronic products	Automotive conducted transient Emission test	Transient Voltage: ± 0.2 V to ± 400 V	ECER10.4: AIS004(PART 3):+A1: AIS004(PART	Permanent



Certificate



Scope



Scope of Accreditation for Testing

As per ISO/IEC 17025:2017

CAB Name: Salicon Nano Technology Pvt. Ltd.

Page No. **16** of **17**

Address: Pawan Puri, Sybly Industrial Area, Near Ganga Canel,
Murad Nagar, Ghaziabad - 201206, U.P

Certificate No.: T-0042

Issue date : 30.03.2026

Validity : 29.03.2030

Amendment date: N/A

Sr. No.	Product or material or equipment used for test	Type of test performed/ characteristic	Range/ limit of detection	Standard specifications/ Equipment/Techniques used	Facility
			Pulse Rise Time: 5 ns to 1 ms Pulse Duration: 50 ns to 10 ms Frequency Range: DC to 400 MHz Current Measurement: 0 A to 100 A peak Load Dump Voltage (Pulse 5b): up to 174 V	3):Rev1:ISO 7637-2:Clause 5.6 - 5.6.5ISO7637-2:Clause 4.2-4.4ECER10.05:ECE R10.06	
61	Electrical/Electronic products	Immunity to Voltage Fluctuation test	12V, 10V	IEC 61000-4-14:+AMD1:+AMD2:	Permanent
62	Electrical/Electronic Products	Power Frequency Magnetic Field Immunity test	30A/m	IEC 61000-4-8EN 61000-4-8:	Permanent
63	Electrical/Electronic subassembly and Vehicle	Power Frequency Magnetic Field Immunity test	30A/m	IEC 61851-21-2:	Permanent
64	Network Telecommunication Equipment	Conducted Immunity Measurement	150 kHz – 80 MHz	GR1089	Permanent
65	Network Telecommunication product	RF Radiated Susceptibility test	80 MHz – 6 GHz	GR 1089:G R 1089	Permanent
66	Network Telecommunication product	Conducted Emission Test	150 kHz – 30 MHz	GR 1089 (GR 1089	Permanent



Certificate



Scope



International Quality And Accreditation Services Pvt. Ltd.
(Formerly International Quality And Accreditation Services LLP)
1/4, 1st Floor, East Patel Nagar New Delhi, 110008

Scope of Accreditation for Testing

As per ISO/IEC 17025:2017

CAB Name:

Salicon Nano Technology Pvt. Ltd.

Page No. 17 of 17

Address:

Pawan Puri, Sybly Industrial Area, Near Ganga Canal,
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Certificate No.:

T-0042

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Sr. No.	Product or material or equipment used for test	Type of test performed/ characteristic	Range/ limit of detection	Standard specifications/ Equipment/Techniques used	Facility
67	Vehicles, boats and internal combustion engines	Conducted Emission Test	150 kHz – 108 MHz	CISPR 25:Clause 6.5	Permanent
68	Electrical Lighting and Similar equipment	Radiated Emission Test (LLA)	9kHz – 30MHz	CISPR 15:, EN 55015:+A1:Clause 4.5.2 – 4.5.3	Permanent
69	Electrical Lighting and Similar equipment	Conducted Emission Test	9 kHz -30 MHz	CISPR 15:EN 55015:+A1: Clause 4.3	Permanent
70	Electrical Lighting and Similar equipment	Radiated Emission Test	30MHz – 1GHz	CISPR 15:EN 55015:/A1:	Permanent
71	Household appliances, Electric tools and similar apparatus	Radiated Emission Test	9kHz – 6 GHz	CISPR 14-1:(7 th Edition) Clause 4.3.2 - 4.3.5EN IEC 55014-1:	Permanent
72	Industrial ,Scientific and Medical(ISM), Electrical Equipment	Radiated Emission Test	30 MHz to 18 GHz	IEC 60601-1-2:Clause 7.3EN 60601-1:/A2:	Permanent



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This is annexure to 'Certificate of Accreditation' and does not require any signature

Reg Office: 307/20, 2nd Lane No. 5A, Ranjit Nagar, New Delhi 110008, India



Scope